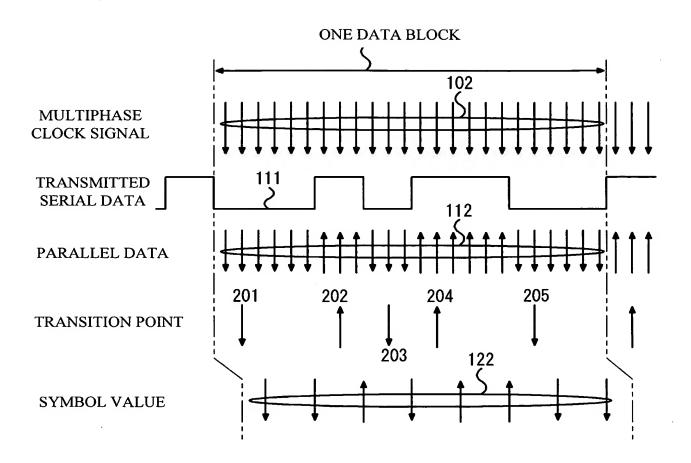


Fig. 2



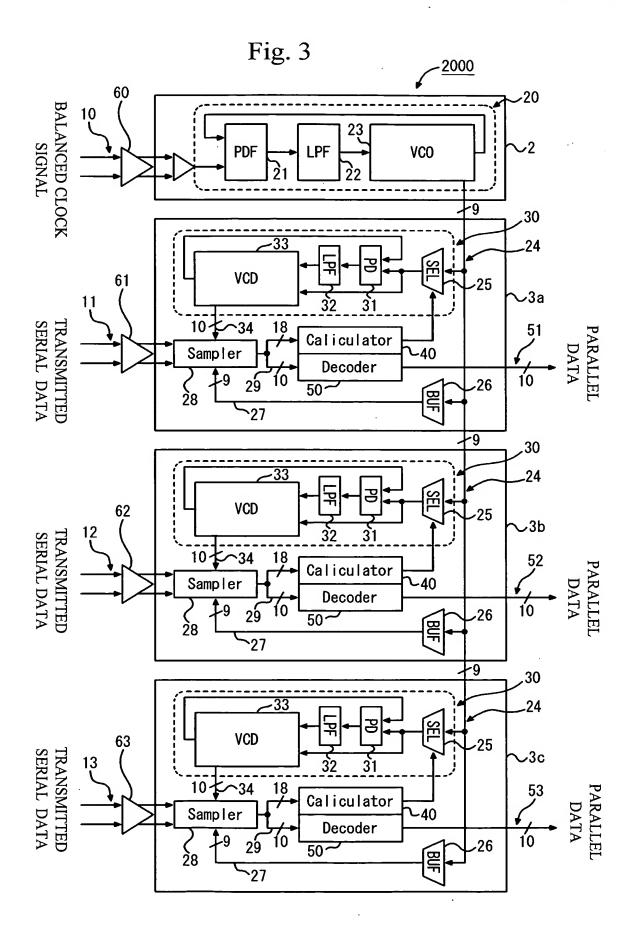
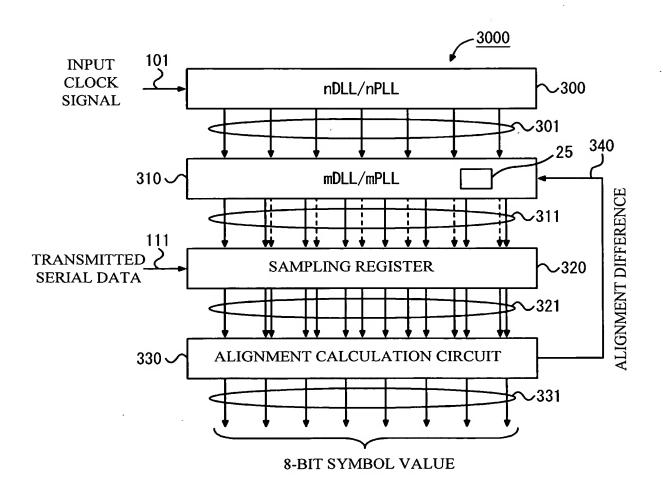
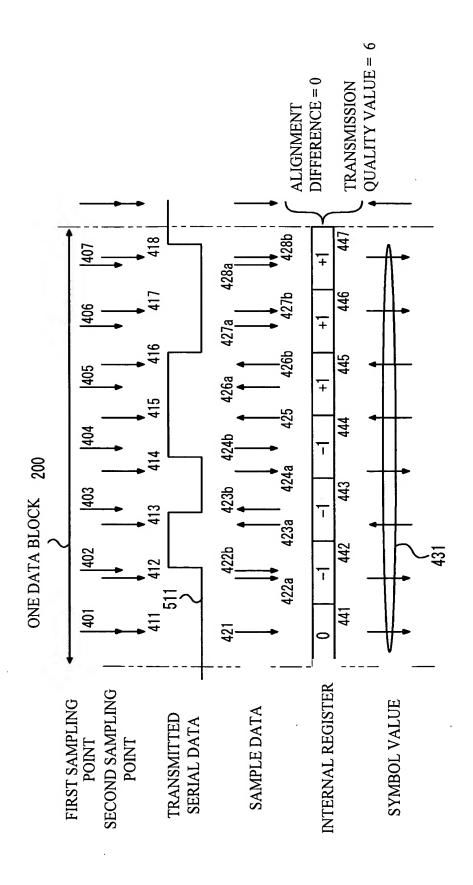


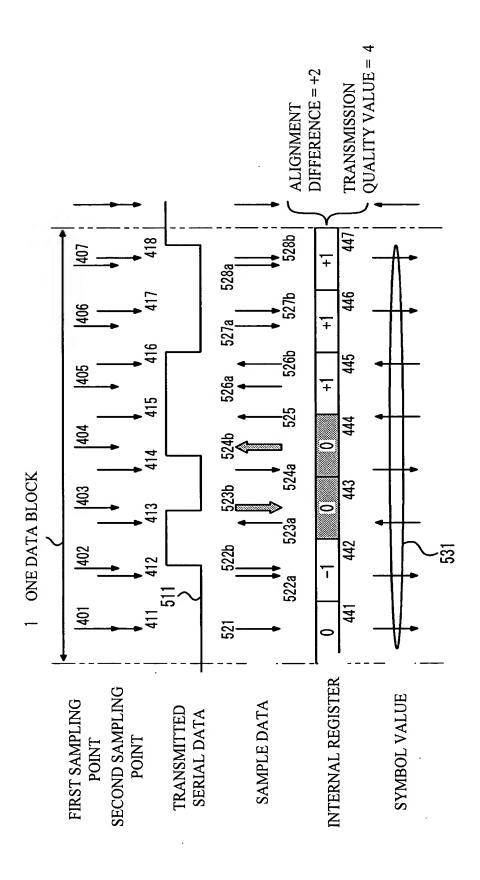
Fig. 4













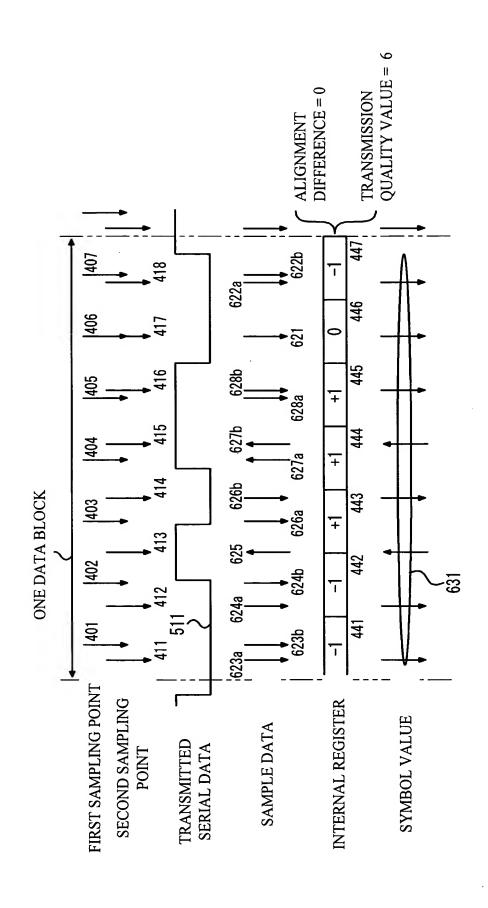


Fig. 8A

This Invention (M/N sampling method)

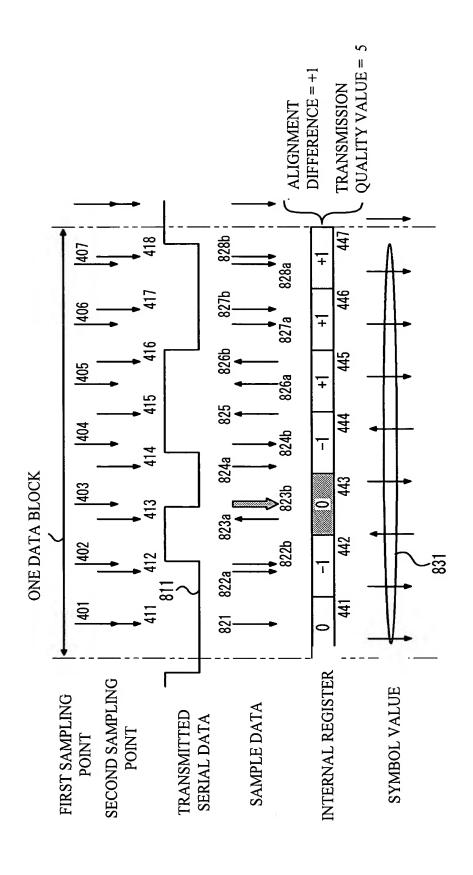
m	n	m/n-1.0	# of CLKs	skew shift(deg)
8	5	0. 60	10	27. 00
8	6	0. 33	12	15. 00
8	7	0. 14	14	6. 43

Fig. 8B

Prior Art (X sampling method)

m	Х	 # of CLKs	skew shift(deg)
8	3	 24	15. 00
8	4	 32	11. 25





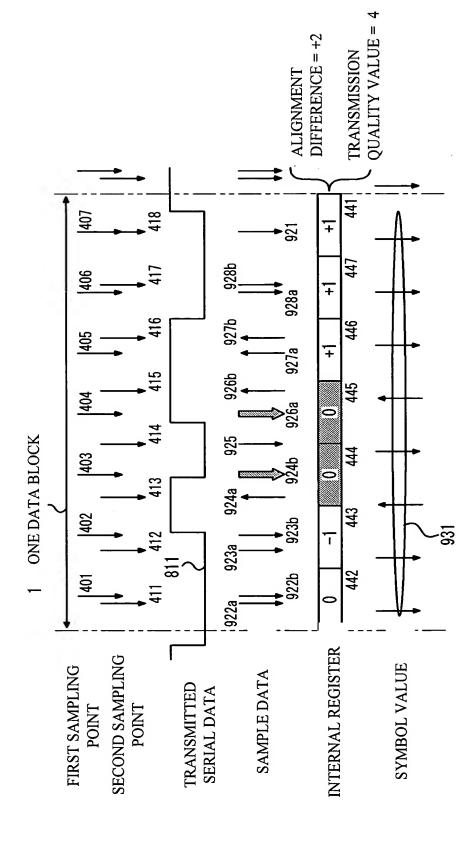
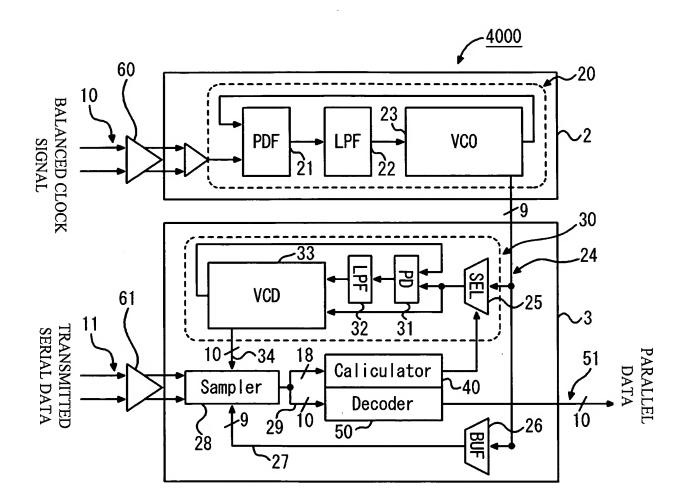


Fig. 10

Fig. 11



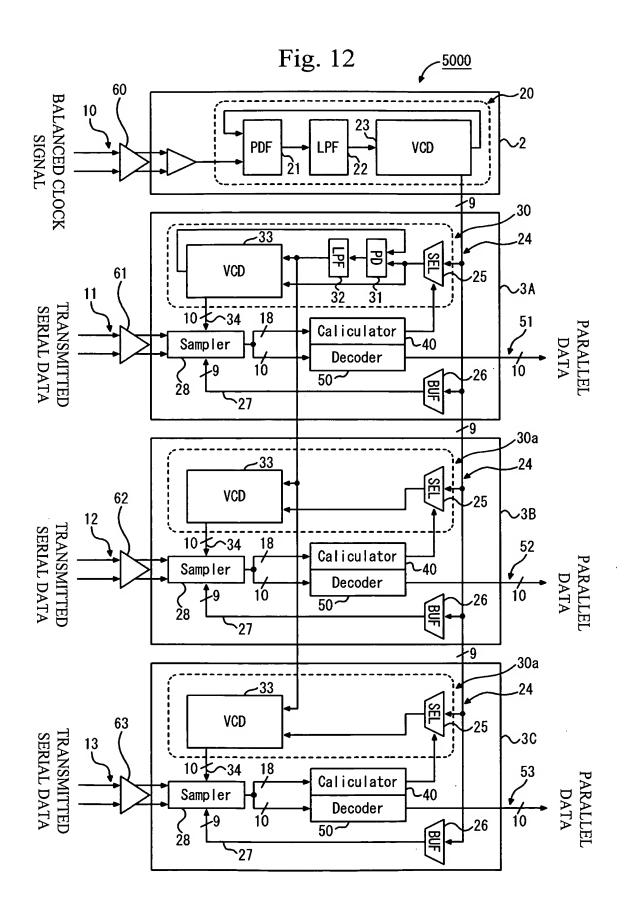


Fig. 13

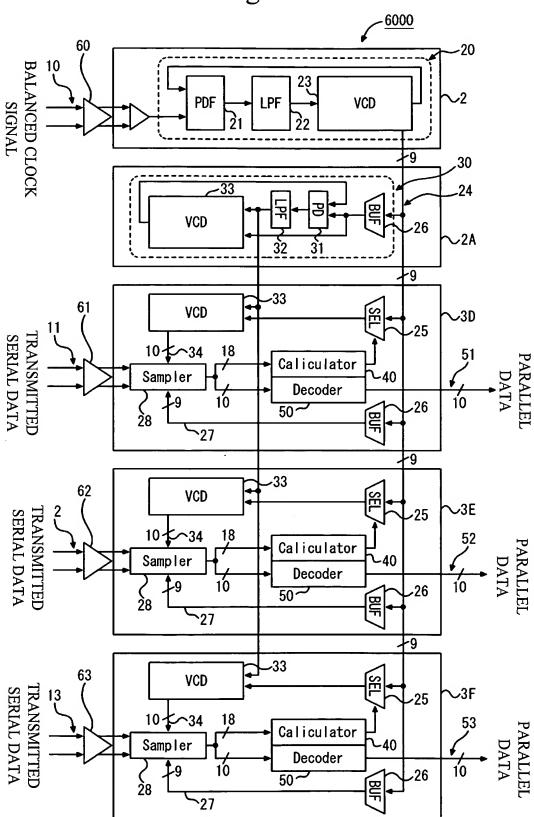


Fig. 14

